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Application/Control No.	Applicant(s)/Patent under Reexamination
10/786,376	YANG ET AL
Examiner	Art Unit
Jia W. Lu	2634

	SEARCHED		
Class	Subclass	Date	Examiner
375	319	7/27/2005	JL
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
375	319	7/28/2005	JL

SEARCH NOT (INCLUDING SEARCH :) :
	DATE	EXMR
EAST-USPAT, USPGPUB, EPO, JPO, DERWENT, IBM (See Search History Printout)	7/28/2005	JL
INVENTORSHIP (ON PALM)	7/28/2005	JL
IEEE keyword search - Advanced Search - Modulation format and DC offset	7/28/2005	JL
Google Web Search - Modulation format/techniques and DC/zero-offset	7/28/2005	JL
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